• Supplementary File •

## Silicon-based inorganic-organic hybrid optoelectronic synaptic devices simulating cross-modal learning

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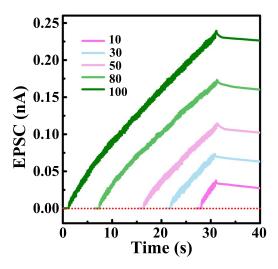


Figure S1 EPSC of a synaptic transistor triggered by i (i = 10, 30, 50, 80 and 100) optical spikes. Each optical spike has the wavelength, power density and duration of 532 nm, 3.5 mW/cm<sup>2</sup> and 200 ms, respectively.

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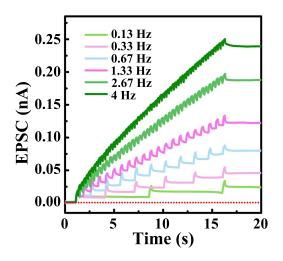


Figure S2 EPSC of a synaptic transistor triggered by optical spikes with frequencies ranging from 0.13 to 4 Hz. Each optical spike has the wavelength, power density and duration of 532 nm,  $3.5 \text{ mW/cm}^2$  and 200 ms, respectively.

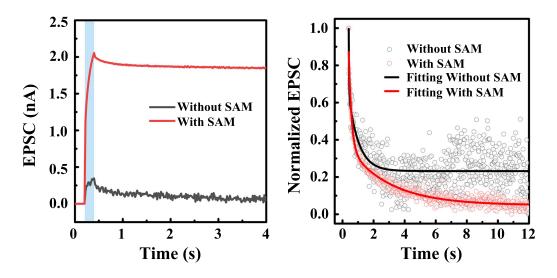


Figure S3 (a) EPSCs of the synaptic devices with/without the surface modification of the gate oxide of SiO<sub>2</sub>. (The EPSC without the surface modification has been multiplied by 10.) (b) Normalized EPSC decay curves of the synaptic devices with/without the surface modification of the gate oxide of SiO<sub>2</sub>. (3-aminopropyl) trimethoxysilane (APTMS) is used for the surface modification.